

**DESIGN/PROCESS CHANGE NOTIFICATION**

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

**Implementation of change:**

Expected First Shipment Date for Changed Product : May. 05, 2013

Expected First Date Code of Changed Product :1327

Description of Change (From) :  
5/6-in wafer fabrication line at Fairchild Semiconductor Bucheon Korea.

Description of Change (To) :  
8-in wafer fabrication line at Fairchild Semiconductor Bucheon Korea.

Reason for Change:  
Fairchild Semiconductor is increasing wafer fabrication capacity by qualifying an 8-in wafer fabrication line at Fairchild Semiconductor Bucheon Korea. Quality and reliability remain at the highest standards already demonstrated within Fairchild's existing products. The reliability qualification results used to qualify the 8-in wafer fabrication line are summarized below. The specific groups of products/MOSFET technologies are listed in the affected FSIDs list. Design, die size and layout of the affected products will remain unchanged. There are no changes in the datasheet or electrical performance.

**Affected Product(s):**

FCA20N60	FCA20N60F	FCA20N60FS
FCA20N60S_F109	FCA20N60_F109	FCA35N60
FCA47N60	FCA47N60F	FCA47N60F_SN00171
FCA47N60_F109	FCB11N60TM	FCB20N60FTM
FCB20N60TM	FCBB20CH60SF	FCD4N60TM
FCD5N60TM	FCD5N60TM_WS	FCD7N60TM
FCD7N60TM_WS	FCH35N60	FCH47N60F_F133
FCH47N60_F133	FCI7N60	FCP11N60
FCP11N60F	FCP11N60_G	FCP16N60
FCP16N60_G	FCP190N60	FCP190N60E
FCP20N60	FCP20N60FS	FCP20N60_G
FCP260N60E	FCP380N60	FCP380N60E
FCP4N60	FCP7N60	FCPF11N60
FCPF11N60F	FCPF11N60T	FCPF11N60_G
FCPF11N65	FCPF11N65_G	FCPF16N60
FCPF190N60	FCPF190N60E	FCPF20N60
FCPF20N60FS	FCPF20N60S	FCPF20N60ST
FCPF20N60ST_G	FCPF20N60T	FCPF260N60E
FCPF380N60	FCPF380N60E	FCPF400N60
FCPF7N60	FCPF7N60YDTU	FCU5N60TU
FDA24N40F	FDA24N50	FDA24N50F
FDA28N50	FDA28N50F	FDA33N25
FDA38N30	FDA50N50	FDA59N25
FDA59N30	FDA69N25	FDA70N20
FDB12N50TM	FDB20N50F	FDB28N30TM
FDB33N25TM	FDB44N25TM	FDB52N20TM
FDD3N50NZTM	FDD5N50NZFTM	FDD5N50NZTM
FDD6N20TM	FDD6N25TM	FDD6N50FTM
FDD8N50NZTM	FDH45N50F_F133	FDH50N50_F133
FDL100N50F	FDP12N50NZ	FDP15N40
FDP18N20F	FDP19N40	FDP22N50N
FDP24N40	FDP26N40	FDP33N25
FDP39N20	FDP51N25	FDP52N20
FDP5N50NZ	FDP61N20	FDP8N50NZ
FDPF12N50NZ	FDPF13N50NZ	FDPF18N20FT
FDPF33N25T	FDPF33N25TRDTU	FDPF39N20
FDPF39N20TLDTU	FDPF3N50NZ	FDPF44N25T
FDPF51N25	FDPF51N25RDTU	FDPF51N25YDTU
FDPF5N50NZ	FDPF5N50NZF	FDPF5N50NZFT
FDPF5N50NZU	FDPF8N50NZ	FDPF8N50NZF

**Affected Product(s):**

FDPF8N50NZU	FDPF9N50NZ	FGA40N65SMD
FGD4536TM	FGH20N60SFDTU	FGH20N60UFDTU
FGH40N60SFDTU	FGH40N60SFTU	FGH40N60SMD
FGH40N60SMDF	FGH40N60UFDTU	FGH40N60UFDTU_SN00006
FGH40N60UFTU	FGH40N60UFTU_SN00007	FGH40N65UFDTU
FGH80N60FD2TU	FGH80N60FDTU	FGPF4533
FGPF4533RDTU	FGPF4536	FGPF4536JDTU
FGPF4536YDTU	FGPF4633RDTU	FGPF4633TU
FGPF4636YDTU	PCFC11N60W	PCFC20N60W
PCFC47N60FW	PCFC47N60FW_SN00201	PCFG40N65SMW

Qualification Plan	Device	Package	Process	No. of Lots
Q20120257	FDA59N25	TT3P0003	UniFET1 150~250V	3

Reliability Test	Condition	Standard	Device Name	FDA59N25	FDA59N25	FDA59N25
			Lot No.	Q20120257AA	Q20120257AB	Q20120257AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 5 min on, 3.5 min off	MIL-STD-750-1036	6000 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120259	FDH50N50_F133	TO247003	UniFET1 300~500V (Over 24A)	3

Reliability Test	Condition	Standard	Device Name	FDH50N50_F133	FDH50N50_F133	FDH50N50_F133
			Lot No.	Q20120259AA	Q20120259AB	Q20120259AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150 C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150 C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 5 min on, 3.5 min off	MIL-STD-750-1036	6000 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120260	FDP22N50N	TO220003	UniFET2 500V	3

Reliability Test	Condition	Standard	Device Name	FDP22N50N	FDP22N50N	FDP22N50N
			Lot No.	Q20120260AA	Q20120260AB	Q20120260AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 3.5 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10 sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120263	FCP20N60	TO220003	Super-FET 600V TO220	3

Reliability Test	Condition	Standard	Device Name	FCP20N60	FCP20N60	FCP20N60
			Lot No.	Q20120263AA	Q20120263AB	Q20120263AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 3.5 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10 sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120265	FCB20N60TM	TT263002	Super-FET 600V D2pak	1

Reliability Test	Condition	Standard	Device Name	FCB20N60TM
			Lot No.	Q20120265AA
			Duration	Result/FA
PRECON	L1 245C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 3.5 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120266	FDB52N20TM	TT263002	UNIFET 200V(include 250V /Dpak and D2 pak)	1

Reliability Test	Condition	Standard	Device Name	FDB52N20TM
			Lot No.	Q20120266AA
			Duration	Result/FA
PRECON	L1 245C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 3.5 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77
RSDH	260C	JESD22-B106	15 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120267	FDB12N50TM	TT263002	UNIFET1 300-500V_D2pak	1

Reliability Test	Condition	Standard	Device Name	FDB12N50TM
			Lot No.	Q20120267AA
			Duration	Result/FA
PRECON	L1 245C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120268	FCA47N60	TT3P0003	SuperFET 600V TO3P/TO247	1

Reliability Test	Condition	Standard	Device Name	FCA47N60
			Lot No.	Q20120268AA
			Duration	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 5 min on, 3.5 min off	MIL-STD-750-1036	6000 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77



Qualification Plan	Device	Package	Process	No. of Lots
Q20120269	FGD4536TM	TT252003	PDP 4GEN Trench IGBT_360V Dpak	1

Reliability Test	Condition	Standard	Device Name	FGD4536TM
			Lot No.	Q20120269AA
			Duration	Result/FA
PRECON	L1 260C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	10000 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120270	FCD7N60TM	TT252002	SuperFET_600V Dpak	1

Reliability Test	Condition	Standard	Device Name	FCD7N60TM
			Lot No.	Q20120270AA
			Duration	Result/FA
PRECON	L1 260C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	10000 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120271	FDD7N60NZTM	TT252003	UniFET2 600V Dpak	1

Reliability Test	Condition	Standard	Device Name	FDD7N60NZTM
			Lot No.	Q20120271AA
			Duration	Result/FA
PRECON	L1 260°C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	10000 cycles	0/77
RSDH	260C	JESD22-B106	10sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120272	FCP190N60	TT220003	Super-FET2 600V	3

Reliability Test	Condition	Standard	Device Name	FCP190N60	FCP190N60	FCP190N60
			Lot No.	Q20120272AA	Q20120272AB	Q20120272AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10 sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120273	FCPF190N60	TF22S003	SuperFET2 600V TO220F	1

Reliability Test	Condition	Standard	Device Name	FCPF190N60
			Lot No.	Q20120273AA
			Duration	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20120277	FDD6N50TM	TT252002	UniFET1 300-500V/Dpak Ipak	1

Reliability Test	Condition	Standard	Device Name	FDD6N50TM
			Lot No.	Q20120277AA
			Duration	Result/FA
PRECON	L1 260°C	JESD22-A113	5 Cycles 24 hrs	0/154
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	10000 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130022A	FCB20N60FTM	TT263002	SuperFET FR FET	2
	FCH47N60F_F133	TO247003		1

Reliability Test	Condition	Standard	Device Name	FCB20N60FTM	FCB20N60FTM	FCH47N60F_F133
			Lot No.	Q20130022AA	Q20130022AB	Q20130022BA
			Duration	Result/FA	Result/FA	Result/FA
PRECON	L1 245°C	JESD22-A113	5 Cycles 24 hrs	0/154	0/154	-
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles 5000 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10 sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130023	FGPF4633TU	TF22S003	PDP 4GEN Trench IGBT 330V_360V TO220F	3

Reliability Test	Condition	Standard	Device Name	FGPF4633TU	FGPF4633TU	FGPF4633TU
			Lot No.	Q20130023AA	Q20130023AB	Q20130023AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77	0/77	0/77
RSDH	260C	JESD22-B106	10 sec	0/30	0/30	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130024	FCP20N60	TO220003	Super-FET 600V TO220	1

Reliability Test	Condition	Standard	Device Name	FCP20N60
			Lot No.	Q20130024AA
			Duration	Result/FA
HTGB	100 % Rated VGS, Tj max=150C	JESD22-A108	1000hrs	0/77
HTRB	80% of Rated BV, Tj max=150C	JESD22-A108	1000hrs	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77
PRCL	Delta 100C, 2 min on, 3.5 min off	MIL-STD-750-1036	8572 cycles	0/77
RSDH	260C	JESD22-B106	10 sec	0/30
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130020	FGH40N60SMD	TO247003	FS IGBT 600V	3

Reliability Test	Condition	Standard	Device Name	FGH40N60SMD	FGH40N60SMD	FGH40N60SMD
			Lot No.	Q20130020AA	Q20130020AB	Q20130020AC
			Duration	Result/FA	Result/FA	Result/FA
HTGB	100 % Rated VGS, Tj max=175C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTRB	80% of Rated BV, Tj max=175C	JESD22-A108	1000hrs	0/77	0/77	0/77
HTSL	150 C	JESD22-A103	1000hrs	0/77	0/77	0/77
HAST	130 C, 85% RH, Vds=42V	JESD22-A110	96hrs	0/77	0/77	0/77
PRCL	Delta 100C, 5 min on, 5 min off	MIL-STD-750-1036	6000 cycles	0/77	0/77	0/77
TMCL	-65 C to 150 C, 30 min/ cycles	JESD22-A104	500 cycles	0/77	0/77	0/77